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**OFFICE OF PETITIONS**

In re Application of  
Venkateswar R. Kowkutla, et al.  
Application No. 09/945,027  
Filed: August 31, 2001  
Attorney Docket No. TI-31681

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ON PETITION

This is a decision on the petition, filed January 29, 2004, to revive the above-identified application under the provisions of 37 CFR 1.137(b). The delay in responding is regretted; however, the petition was just recently referred to the Office of Petitions for consideration.

The application became abandoned for a failure to reply in a timely manner to the non-final Office action mailed June 17, 2003. A Notice of Abandonment was mailed on January 14, 2004. In response, on January 29, 2004, an amendment and the present petition were filed.

37 CFR 1.137(b)(3) requires a statement that the entire delay in filing the required reply from the due date for the reply until the filing of a grantable petition pursuant to 37 CFR 1.137(b) was unintentional. Although the statement contained in the petition varies from the language required by 37 CFR 1.137(b)(3), the statement will be construed as the statement required by 37 CFR 1.137(b)(3). Petitioner must notify the Office if this is **not** a correct interpretation of the statement contained in the instant petition.

The petition is **GRANTED**.

Telephone inquiries concerning this decision may be directed to the undersigned at (571) 272-3204. All other inquiries regarding this application should be directed to the Technology Center.

The application file is being forwarded to Technology Center AU 2819 for consideration of the amendment filed July 13, 2004.

Sherry D. Brinkley  
Petitions Examiner  
Office of Petitions  
Office of the Deputy Commissioner  
for Patent Examination Policy